DTM63356H

4 GB - 240-Pin Registered DDR2 DIMM ECC with CMD/ADD Parity

Identification

DTM63356H 512Mx72
4GB 2Rx4 PC2-5300P-555-12AF0

Performance Range

Clock / Module Speed / CL-t_{RCD} -t_{RP}

333 MHz / DDR2-667 / 5-5-5
267 MHz / DDR2-533 / 4-4-4
200 MHz / DDR2-400 / 3-3-3

Features

- 240-pin JEDEC-compliant DIMM
- Operating Voltage: 1.8 V ±0.1
- I/O Type: SSTL_18
- Data Transfer Rate: 5.3 Gigabytes/sec
- Data Bursts: 4 or 8 bits, Sequential or Interleaved ordering
- Error Checking and Correction (ECC) bits
- Programmable I/O driver strength (OCD)
- Programmable On-Die Termination (ODT)
- Programmable CAS Latency: 3, 4 or 5
- Differential/Single-Ended Data Strobe signals
- SDRAM Addressing (Row/Col/Bank): 14/11/3
- Fully RoHS Compliant

Description

DTM63356H is a Registered 512Mx72 memory module, which conforms to JEDEC's DDR2 PC2-5300 standard. The assembly is comprised of two Ranks of 36 CMOS 256Mx4 DDR2 Samsung Synchronous DRAMs, two Registers, one Phase-Locked Loop (PLL), and one 2K-bit EEPROM used for Serial Presence Detect.

Both output driver strength and input termination impedance are programmable to maintain signal integrity on the I/O signals. Error Checking and Correction bits are provided to ensure data integrity. The module supports Intel SDDC and Chipkill advanced ECC features.

The Data Strobe signals may be used either as differential pairs, or as single-ended strobes, with the /DQS signals disabled.

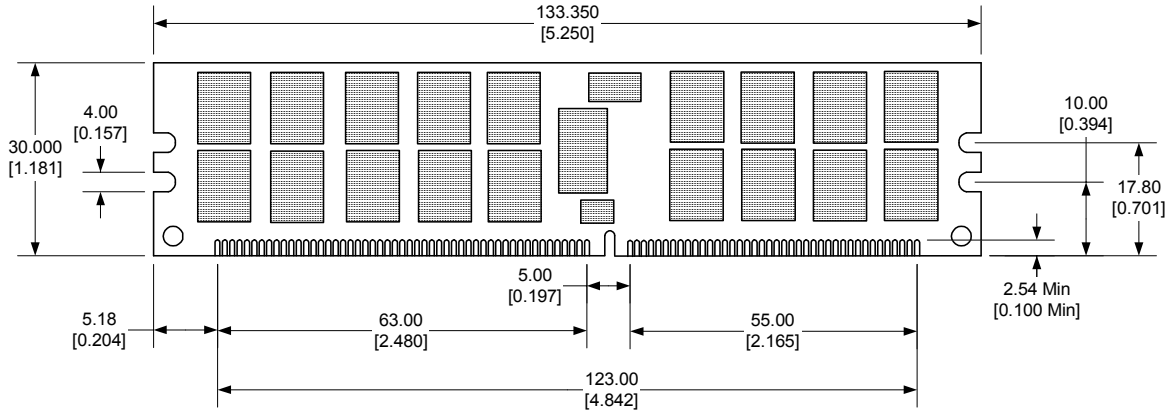
Pin Configuration

Front Side				Back Side			
1 VREF	31 DQ19	61 A4	91 GND	121 GND	151 GND	181 VDD	211 DQS14
2 GND	32 GND	62 VDD	92 /DQS5	122 DQ4	152 DQ28	182 A3	212 /DQS14
3 DQ0	33 DQ24	63 A2	93 DQS5	123 DQ5	153 DQ29	183 A1	213 GND
4 DQ1	34 DQ25	64 VDD	94 GND	124 GND	154 GND	184 VDD	214 DQ46
5 GND	35 GND	65 GND	95 DQ42	125 DQS9	155 DQS12	185 CK0	215 DQ47
6 /DQS0	36 /DQS3	66 GND	96 DQ43	126 /DQS9	156 /DQS12	186 /CK0	216 GND
7 DQS0	37 DQS3	67 VDD	97 GND	127 GND	157 GND	187 VDD	217 DQ52
8 GND	38 GND	68 Par_In	98 DQ48	128 DQ6	158 DQ30	188 A0	218 DQ53
9 DQ2	39 DQ26	69 VDD	99 DQ49	129 DQ7	159 DQ31	189 VDD	219 GND
10 DQ3	40 DQ27	70 A10	100 GND	130 GND	160 GND	190 BA1	220 NC
11 GND	41 GND	71 BA0	101 SA2	131 DQ12	161 CB4	191 VDD	221 NC
12 DQ8	42 CB0	72 VDD	102 NC	132 DQ13	162 CB5	192 /RAS	222 GND
13 DQ9	43 CB1	73 /WE	103 GND	133 GND	163 GND	193 /S0	223 DQS15
14 GND	44 GND	74 /CAS	104 /DQS6	134 DQS10	164 DQS17	194 VDD	224 /DQS15
15 /DQS1	45 /DQS8	75 VDD	105 DQS6	135 /DQS10	165 /DQS17	195 ODT0	225 GND
16 DQS1	46 DQS8	76 /S1	106 GND	136 GND	166 GND	196 A13	226 DQ54
17 GND	47 GND	77 ODT1	107 DQ50	137 NC	167 CB6	197 VDD	227 DQ55
18 /RESET	48 CB2	78 VDD	108 DQ51	138 NC	168 CB7	198 GND	228 GND
19 NC	49 CB3	79 GND	109 GND	139 GND	169 GND	199 DQ36	229 DQ60
20 GND	50 GND	80 DQ32	110 DQ56	140 DQ14	170 VDD	200 DQ37	230 DQ61
21 DQ10	51 VDD	81 DQ33	111 DQ57	141 DQ15	171 CKE1	201 GND	231 GND
22 DQ11	52 CKE0	82 GND	112 GND	142 GND	172 VDD	202 DQS13	232 DQS16
23 GND	53 VDD	83 /DQS4	113 /DQS7	143 DQ20	173 A15	203 /DQS13	233 /DQS16
24 DQ16	54 BA2	84 DQS4	114 DQS7	144 DQ21	174 A14	204 GND	234 GND
25 DQ17	55 /Err_Out	85 GND	115 GND	145 GND	175 VDD	205 DQ38	235 DQ62
26 GND	56 VDD	86 DQ34	116 DQ58	146 DQS11	176 A12	206 DQ39	236 DQ63
27 /DQS2	57 A11	87 DQ35	117 DQ59	147 /DQS11	177 A9	207 GND	237 GND
28 DQS2	58 A7	88 GND	118 GND	148 GND	178 VDD	208 DQ44	238 VDDSPD
29 GND	59 VDD	89 DQ40	119 SDA	149 DQ22	179 A8	209 DQ45	239 SA0
30 DQ18	60 A5	90 DQ41	120 SCL	150 DQ23	180 A6	210 GND	240 SA1

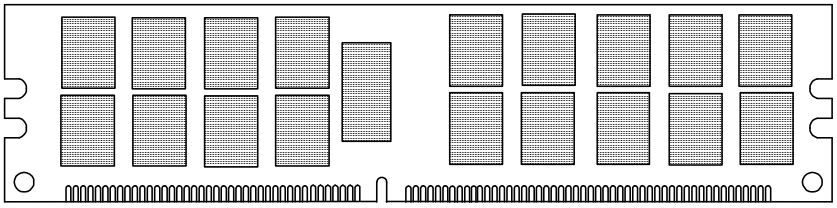
Pin Description

Name	Function
/CAS	Column Address Strobe
/Err_Out	Parity Error Found
/RAS	Row Address Strobe
/RESET	Register and PLL Reset
/S[1:0]	Chip Selects
/WE	Write Enable
A[15:0]	Address Inputs
BA[2:0]	Bank Addresses
CB[7:0]	Data Check Bits
CK0, /CK0	Differential Clock Inputs
CKE[1:0]	Clock Enables
DQ[63:0]	Data Bits
DQS[17:0], /DQS[17:0]	Differential Data Strobes
GND	Ground
NC	No Connection
ODT[1:0]	On Die Termination Inputs
Par_In	Parity Bit, Address & Control
SA[2:0]	SPD Address
SCL	SPD Clock Input
SDA	SPD Data Input/Output
VDD	Power
VDDSPD	SPD EEPROM Power
VREF	Reference Voltage

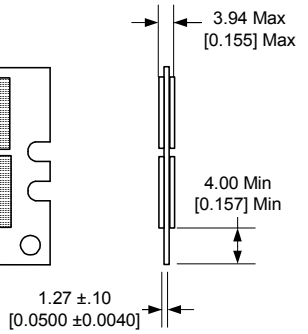
Front view



Back view



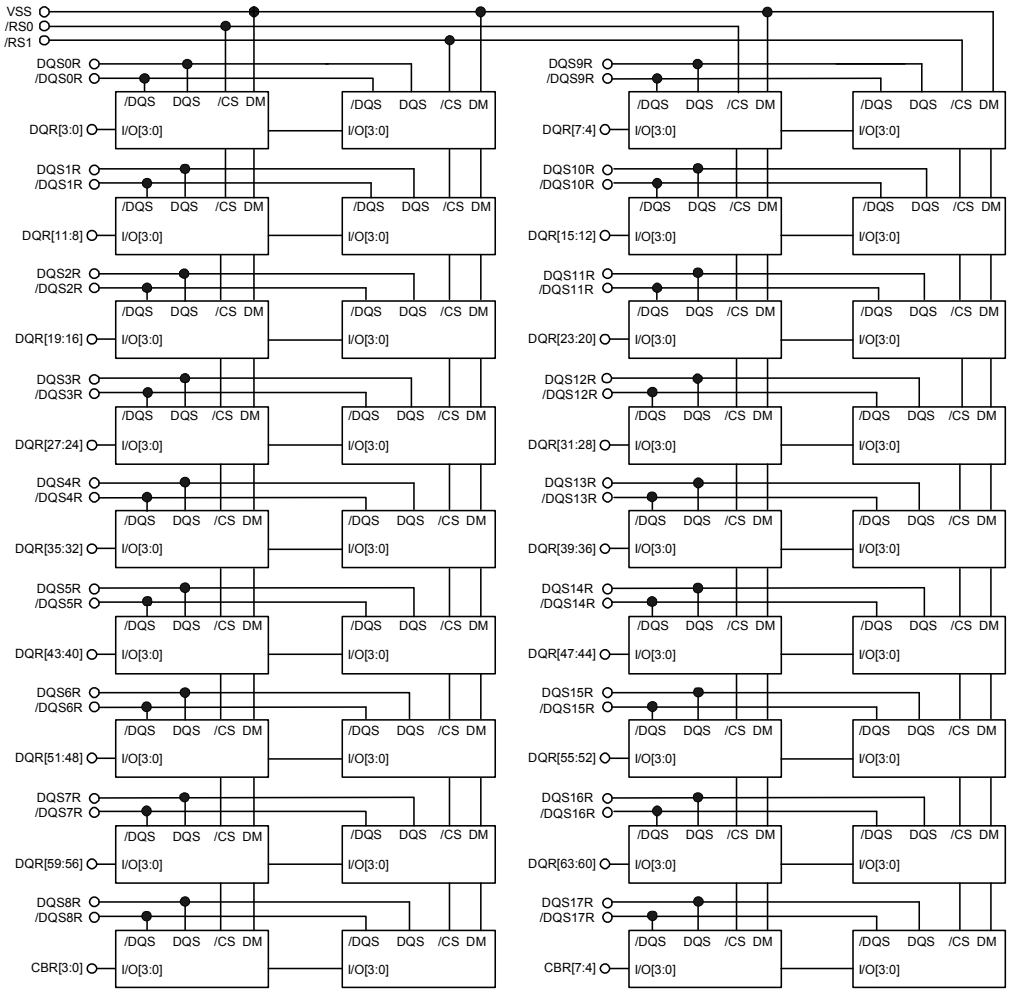
Side view



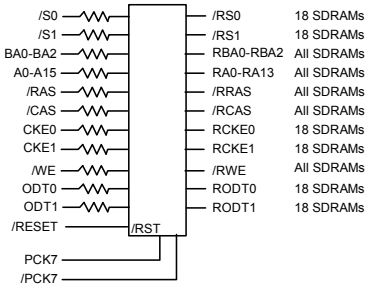
Notes

Tolerances on all dimensions (except where otherwise indicated) are ±.13 (.005).

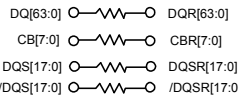
All dimensions are expressed as: millimeters [inches]



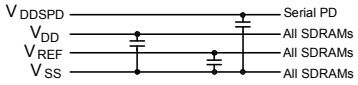
REGISTERS

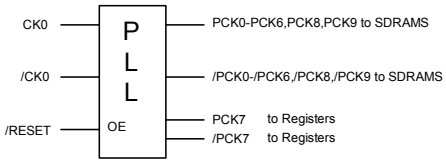


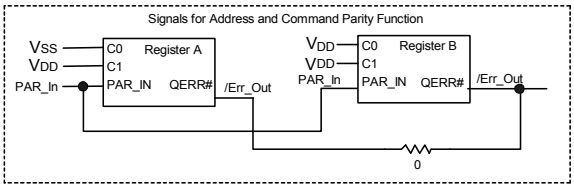
Notes:
1. Unless otherwise noted, resistor values are 22 Ohms ±5%

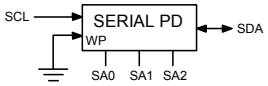


DECOUPLING









Absolute Maximum Ratings
(Note: Operation at or above Absolute Maximum Ratings can adversely affect module reliability.)

PARAMETER	Symbol	Minimum	Maximum	Unit
Temperature, non-Operating	$T_{STORAGE}$	-55	100	C
DRAM Case Temperature, Operating	T_{CASE}	0	95	C
Voltage on V_{DD} relative to V_{SS}	V_{DD}	-0.5	2.3	V
Voltage on Any Pin relative to V_{SS}	V_{IN},V_{OUT}	-0.5	2.3	V

Recommended DC Operating Conditions (Voltages referenced to V_{ss} = 0 V)

PARAMETER	Symbol	Minimum	Typical	Maximum	Unit	Note
Power Supply Voltage	V_{DD}	1.7	1.8	1.9	V	
I/O Reference Voltage	V_{REF}	0.49 V_{DD}	0.50 V_{DD}	0.51 V_{DD}	V	1
Bus Termination Voltage	V_{TT}	V_{REF} - 0.04	V_{REF}	V_{REF} + 0.04	V	

Notes:
1. The value of V_{REF} is expected to equal one-half V_{DD} and to track variations in the V_{DD} DC level. Peak-to-peak noise on V_{REF} may not exceed ±1% of its DC value.

DC Input Logic Levels, Single-Ended (Voltages referenced to V_{ss} = 0 V)

PARAMETER	Symbol	Minimum	Maximum	Unit
Logical High (Logic 1)	$V_{IH(DC)}$	V_{REF} + 0.125	V_{DD} + 0.300	V
Logical Low (Logic 0)	$V_{IL(DC)}$	-0.300	V_{REF} - 0.125	V

AC Input Logic Levels, Single-Ended (Voltages referenced to V_{ss} = 0 V)

PARAMETER	Symbol	Minimum	Maximum	Unit
Logical High (Logic 1)	$V_{IH(AC)}$	V_{REF} + 0.250	-	V
Logical Low (Logic 0)	$V_{IL(AC)}$	-	V_{REF} - 0.250	V

Differential Input Logic Levels (Voltages referenced to V_{ss} = 0 V)

PARAMETER	Symbol	Minimum	Maximum	Unit	Note
DC Input Signal Voltage	$V_{IN(DC)}$	-0.300	V_{DD} + 0.300	V	1
DC Differential Input Voltage	$V_{ID(DC)}$	-0.250	V_{DD} + 0.600	V	2
AC Differential Input Voltage	$V_{ID(AC)}$	-0.500	V_{DD} + 0.600	V	3
AC Differential Cross-Point Voltage	$V_{IX(AC)}$	0.50 VDD - 0.175	0.50 VDD + 0.175	V	4

Notes:
1. $V_{IN(DC)}$ specifies the allowable DC excursion of each input of a differential pair.
2. $V_{ID(DC)}$ specifies the input differential voltage, *i.e.* the absolute value of the difference between the two voltages of a differential pair.
3. $V_{ID(AC)}$ specifies the input differential voltage required for switching.
4. The typical value of $V_{IX(AC)}$ is expected to be 0.5 V_{DD} and is expected to track variations in V_{DD}.

Capacitance (0 C < T_{CASE} < 55 C, f = 100 MHz, V_{OUT}(DC) = V_{DD}/2, V_{OUT}(ac) = 0.1V(p-p))

PARAMETER	Pin	Symbol	Minimum	Maximum	Unit
Input Capacitance, Clock	CK0, /CK0	CIN1	2	3	pF
Input Capacitance, Address and Control	BA[2:0], A[15:0], /S[1:0], /RAS, /CAS, /WE, CKE[1:0], ODT[1:0]	CIN2	5	7	pF
Input/Output Capacitance	DQ[63:0], CB[7:0], DQS[17:0], /DQS[17:0]	CIO	5	8	pF

DC Characteristics (Voltages referenced to V_{ss} = 0 V)

PARAMETER	Symbol	Minimum	Maximum	Unit	Note
Input Leakage Current	I_{LI}	-10	10	µA	1
Output Leakage Current	I_{OZ}	-10	10	µA	2
Output Minimum Source DC Current	I_{OH}	-13.4	-	mA	3
Output Minimum Sink DC Current	I_{OL}	+13.4	-	mA	4

Notes:
1. These values are guaranteed by design and are tested on a sample basis only
2. DQx and ODT are disabled, and 0 V ≤ V_{OUT} ≤ V_{DD}.
3. V_{DD} = 1.7 V, V_{OUT} = 1420 mV. (V_{OUT} - V_{DD})/I_{OH} must be less than 21 Ohms for values of V_{OUT} between V_{DD} and (V_{DD} - 280 mV).
4. V_{DD} = 1.7 V, V_{OUT} = 280 mV. V_{OUT}/I_{OL} must be less than 21 Ohms for values of V_{OUT} between 0 V and 280 mV.

I_{DD} Specifications and Conditions (Voltages referenced to V_{ss} = 0 V)

PARAMETER	Symbol	Test Condition	Max Value	Unit
Operating One Bank Active-Precharge Current	$I_{DD}0$	CKE is HIGH, /CS is HIGH between valid commands; Address bus inputs are switching; Data bus inputs are switching.	2,076	mA
Operating One Bank Active-Read-Precharge Current	$I_{DD}1$	I_{OUT} = 0 mA; BL = 4, CL = 5, AL = 0; CKE is HIGH, /CS is HIGH between valid commands; Address bus inputs are switching.	2,296	mA
Precharge Power-Down Current	$I_{DD}2P$	All banks idle; CKE is LOW; Other control and address bus inputs are stable; Data bus inputs are floating.	1,220	mA
Precharge Standby Current	$I_{DD}2N$	All banks idle; CKE is HIGH, /CS is HIGH; Other control and address bus inputs are switching; Data bus inputs are switching.	1,564	mA
Active Power-Down Current	$I_{DD}3P(F)$	All banks open; CKE is LOW; Other control and address bus inputs are stable; Data bus inputs are floating. Fast Power-down exit (Mode Register bit 12 = 0)	1,732	mA
Active Standby Current	$I_{DD}3N$	All banks open; t_{RAS} = 70 ms; CKE is HIGH, /CS is HIGH between valid commands; Other control and address bus inputs are switching; Data bus inputs are switching.	1,660	mA
Operating Burst Write Current	$I_{DD}4W$	All banks open, Continuous burst writes; BL = 4, CL = 5 t_{CK}, AL = 0; t_{RAS} = 70 ms, CKE is HIGH, /CS is HIGH between valid commands; Address bus inputs are switching; Data bus inputs are switching.	2,362	mA
Operating Burst Read Current	$I_{DD}4R$	All banks open, Continuous burst reads, I_{OUT} = 0 mA; BL = 4, CL = 5 t_{CK}, AL = 0; t_{RAS} = 70 ms; CKE is HIGH, /CS is HIGH between valid commands; Address bus inputs are switching; Data bus inputs are switching.	2,560	mA
Burst Refresh Current	$I_{DD}5B$	Refresh command at every 127.5 ns; CKE is HIGH, /CS is HIGH between valid commands; Other control and address bus inputs are switching; Data bus inputs are switching.	3,232	mA
Self Refresh Current	$I_{DD}6$	CK and /CK at 0 V; CKE ≤ 0.2 V; Other control and address bus inputs are floating; Data bus inputs are floating.	360	mA
Operating Bank Interleave Read Current	$I_{DD}7$	All bank interleaving reads, I_{OUT}= 0 mA; BL = 4, CL = 5 t_{CK}; AL = 12 ns; t_{RRD} = 7.5 ns; CKE is HIGH, /CS is HIGH between valid commands; Address bus inputs are stable during deselects; Data bus inputs are switching.	4,420	mA

Notes: 1. For all $I_{DD}X$ measurements, t_{CK} = 3.0 ns, t_{RC} = 60 ns, t_{RCD} = 15 ns, t_{RAS} = 45 ns, and t_{RP} = 15 ns unless otherwise specified.
2. All $I_{DD}X$ values shown are worst-case maximums, considering all DRAMs, Registers, and the PLL.
3. For all $I_{DD}X$ measurements one rank active, the other rank is in IDD2P Precharge Power-Down mode

AC Operating Conditions

PARAMETER	Symbol	Min	Max	Unit
DQ Output Access Time from Clock	t_{AC}	-450	+450	ps
CAS-to-CAS Command Delay	t_{CCD}	2	-	t_{CK}
Clock High Level Width	t_{CH}	0.45	0.55	t_{CK}
Clock Cycle Time	t_{CK}	3000	8000	ps
Clock Low Level Width	t_{CL}	0.45	0.55	t_{CK}
Data Input Hold Time after DQS Strobe	t_{DH}	0.18	-	ns
DQ Input Pulse Width	t_{DIPW}	0.35	-	t_{CK}
DQS Output Access Time from Clock	t_{DQSCK}	-400	+400	ps
Write DQS High Level Width	t_{DQSH}	0.35	-	t_{CK}
Write DQS Low Level Width	t_{DQSL}	0.35	-	t_{CK}
DQS-Out Edge to Data-Out Edge Skew	t_{DQSQ}	-	240	ps
Data Input Setup Time Before DQS Strobe	t_{DS}	100	-	ps
DQS Falling Edge from Clock, Hold Time	t_{DSH}	0.2	-	t_{CK}
DQS Falling Edge to Clock, Setup Time	t_{DSS}	0.2	-	t_{CK}
Clock Half Period	t_{HP}	minimum of t_{CH} or t_{CL}	-	ns
Address and Command Hold Time after Clock	t_{IH}	0.275	-	ns
Address and Command Setup Time before Clock	t_{IS}	0.200	-	ns
Load Mode Command Cycle Time	t_{MRD}	2	-	t_{CK}
DQ-to-DQS Hold	t_{QH}	t_{HP} - t_{QHS}	-	-
Data Hold Skew Factor	t_{QHS}	-	340	ps
Active-to-Precharge Time	t_{RAS}	45	70K	ns
Active-to-Active / Auto Refresh Time	t_{RC}	60	-	ns
RAS-to-CAS Delay	t_{RCD}	15	-	ns
Average Periodic Refresh Interval	t_{REFI}	-	7.8	µs
Auto Refresh Row Cycle Time	t_{RFC}	127.5	-	ns
Row Precharge Time	t_{RP}	15	-	ns
Read DQS Preamble Time	t_{RPRE}	0.9	1.1	t_{CK}
Read DQS Postamble Time	t_{RPST}	0.4	0.6	t_{CK}
Row Active to Row Active Delay	t_{RRD}	7.5	-	ns
Internal Read to Precharge Command Delay	t_{RTP}	7.5	-	ns
Write DQS Preamble Setup Time	t_{WPRE}	0.35	-	t_{CK}
Write DQS Postamble Time	t_{WPST}	0.4	0.6	t_{CK}
Write Recovery Time	t_{WR}	15	-	ns
Internal Write to Read Command Delay	t_{WTR}	7.5	-	ns
Exit Self Refresh to Non-Read Command	t_{XSNR}	t_{RFC}(min) + 10	-	ns
Exit Self Refresh to Read Command	t_{XSRD}	200	-	t_{CK}

SERIAL PRESENCE DETECT MATRIX

Byte#	Function.	Value	Hex
0	Number of Bytes Utilized by Module Manufacturer	128 bytes	80
1	Total number of Bytes in SPD device	256 bytes	08
2	Memory Type	DDR2 SDRAM	08
3	Number of Row Addresses	14	0E
4	Number of Column Addresses	11	0B
5	Module Attributes - Number of Ranks, Package and Height		61
	# of Ranks -	2	
	Card on Card -	No	
	DRAM Package -	Planar	
	Module Height -	30mm	
6	Module Data Width.	72	48
7	Reserved	UNUSED	00
8	Voltage Interface Level of this assembly	SSTL/1.8V	05
9	SDRAM Cycle time. (Max. Supported CAS latency). CL=X (tCK) ns	3	30
10	SDRAM Access from Clock. (Highest CAS latency). (tAC) ns	0.45	45
11	DIMM configuration type (Non-parity, Parity or ECC)		06
	Data Parity -		
	Data ECC -	X	
	Address/Command Parity -	X	
	TBD -		
	TBD -		
	TBD -		
	TBD -		
	TBD -		
12	Refresh Rate/Type (µs)	7.8 (SR)	82
13	Primary SDRAM Width	4	04
14	Error Checking SDRAM Width	4	04
15	Reserved	UNUSED	00
16	SDRAM Device Attributes: Burst Lengths Supported		0C
	TBD -		
	TBD -		
	Burst Length = 4 -	X	
	Burst Length = 8 -	X	
	TBD -		
	TBD -		

	TBD -		
	TBD -		
17	SDRAM Device Attributes - Number of Banks on SDRAM Device	8	08
18	SDRAM Device Attributes: CAS Latency		38
	TBD -		
	TBD -		
	Latency = 2 -		
	Latency = 3 -	X	
	Latency = 4 -	X	
	Latency = 5 -	X	
	Latency = 6 -		
	TBD -		
19	DIMM Mechanical Characteristics. Max. module thickness. (mm)	x ≤ 4.10	01
20	DIMM type information		01
	Regular RDIMM (133.35mm) -	X	
	Regular UDIMM (133.35mm) -		
	SODIMM (67.6mm) -		
	Micro-DIMM (45.5mm) -		
	Mini RDIMM (82.0mm) -		
	Mini UDIMM (82.0mm) -		
	TBD -		
	TBD -		
21	SDRAM Module Attributes (Refer to Byte20 for DIMM type information).		05
	Number of active registers on the DIMM (N/A for UDIMM) -	2	
	Number of PLLs on the DIMM (N/A for UDIMM) -	1	
	FET Switch External Enable -	No	
	TBD -		
	Analysis probe installed -	No	
	TBD -		
22	SDRAM Device Attributes: General		03
	Includes Weak Driver -	X	
	Supports 50 ohm ODT -	X	
	Supports PASR (Partial Array Self Refresh) -		
	TBD -		
	TBD -		
	TBD -		
	TBD -		
	TBD -		
23	Minimum Clock Cycle Time at Reduced CAS Latency, CL = X-1 (ns)	3.75	3D
24	Maximum Data Access Time (tAC) from Clock at CL = X- 1 (ns)	0.50	50

25	Minimum Clock Cycle Time at CL = X-2 (ns)	0.50	50
26	Maximum Data Access Time (tAC) from Clock at CL = X-2 (ns)	0.50	60
27	Minimum Row Precharge Time (tRP) (ns)	15	3C
28	Minimum Row Active to Row Active Delay (tRRD) (ns)	7.5	1E
29	Minimum RAS to CAS Delay (tRCD) (ns)	15	3C
30	Minimum Active to Precharge Time (tRAS) (ns)	45	2D
31	Module Rank Density	2GB	02
32	Address and Command Setup Time Before Clock (tIS) (ns)	0.2	20
33	Address and Command Hold Time After Clock (tIH) (ns)	0.27	27
34	Data Input Setup Time Before Strobe (tDS) (ns)	0.1	10
35	Data Input Hold Time After Strobe (tDH) (ns)	0.17	17
36	Write Recovery Time (tWR) (ns)	15	3C
37	Internal write to read command delay (tWTR) (ns)	7.5	1E
38	Internal read to precharge command delay (tRTP) (ns)	7.5	1E
39	Memory Analysis Probe Characteristics.	UNUSED	00
40	Extension of Byte 41(tRC) and Byte 42 (tRFC) (ns)		06
	Add this value to byte 41 -	0	
	Add this value to byte 42 -	0.5	
41	SDRAM Device Minimum Active to Active/Auto Refresh Time (tRC) (ns)	60	3C
42	SDRAM Device Minimum Auto-Refresh to Active/Auto-Refresh Command Period (tRFC). (ns)	127.5	7F
43	SDRAM Device Maximum Cycle Time (tCK max). (ns)	8	80
44	SDRAM Dev DQS-DQ Skew for DQS & DQ signals (tDQSQ) (ns)	0.24	18
45	DDR SDRAM Device Read Data Hold Skew Factor (tQHS) (ns)	0.34	22
46	PLL Relock Time (µs)	15	0F
47	DRAM maximun Case Temperature Delta. (C).		00
	DT4R4W Delta (Bits 0:3) -	0	
	Tcasemax delta (Bits 7:4) -	0	
48	Thermal Resistance of DRAM Package from Top (Case) to Ambient (Psi T-A DRAM). (C/Watt)	0	00
49	DRAM Case Temperature Rise from Ambient due to Activate-Precharge/ Mode Bits (DT0/Mode Bits). (C).		00
	Bit 0. If "0" DRAM does not support high temperature self-refresh entry -	1	
	Bit 1. If "0" Do not need double refresh rate for the proper operation -	0	
	DT0, (Bits 2:7) -	0	

50	DRAM Case Temperature Rise from Ambient due to Precharge/Quiet Standby (DT2N/DT2Q). (C).	0	00
51	DRAM Case Temperature Rise from Ambient due to Precharge Power-Down (DT2P). (Degree C).	0	00
52	DRAM Case Temperature Rise from Ambient due to Active Standby (DT3N). (Degree C).	0	00
53	DRAM Case temperature Rise from Ambient due to Active Power-Down with Fast PDN Exit (DT3Pfast). (Degree C).	0	00
54	DRAM Case temperature Rise from Ambient due to Active Power-Down with Slow PDN Exit (DT3Pslow). (Degree C).	0	00
55	DRAM Case Temperature Rise from Ambient due to Page Open Burst Read/DT4R4W Mode Bit (DT4R/DT4R4W Mode Bit). (Degree C).		00
	Bit 0. "0" if DT4W is greater than DT4R -	0	
	DT4R, (Bits 1:7) -	0	
56	DRAM Case Temperature Rise from Ambient due to Burst Refresh (DT5B). (Degree C).	0	00
57	DRAM Case Temperature Rise from Ambient due to Bank Interleave Reads with Auto-Precharge (DT7). (C).	0	00
58	Thermal Resistance of PLL Package from Top to Ambient (Psi T-A PLL). (C/Watt).	0	00
59	Thermal Resistance of Register Package from Top to Ambient (Psi T-A Register). (C/Watt).	0	00
60	PLL Case Temperature Rise from Ambient due to PLL Active (DT PLL Active). (Degree C).	0	00
61	Register Case Temperature Rise from Ambient due to Register Active/Mode Bit (DT Register Active/Mode Bit).		00
	Bit 0.If "0"Unit for Bits 2:7 is 0.75C -	0	
	Bit 1. RFU. Default: 0 -	0	
	Register Active,(Bits 2:7) -	0	
62	SPD Revision	Revision 1.2	12
63	Checksum for Bytes 0-62		36
64	Module Manufacturer's JEDEC ID Code	Dataram ID	7F
65	Module Manufacturer's JEDEC ID Code	Dataram ID	91
66-71	Module Manufacturer's JEDEC ID Code	UNUSED	00

72	Module Manufacturing Location	UNUSED	00
73	Module Part Number	D	44
74	Module Part Number	A	41
75	Module Part Number	T	54
76	Module Part Number	A	41
77	Module Part Number	R	52
78	Module Part Number	A	41
79	Module Part Number	M	4D
80	Module Part Number		20
81	Module Part Number	6	36
82	Module Part Number	3	33
83	Module Part Number	3	33
84	Module Part Number	5	35
85	Module Part Number	6	36
86-90	Module Part Number		20
91,92	Module Revision Code		20
93,94	Module Manufacturing Date		20
95-98	Module Serial Number	[*serial number*]	23
99-127	Manufacturer's Specific Data	UNUSED	00

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